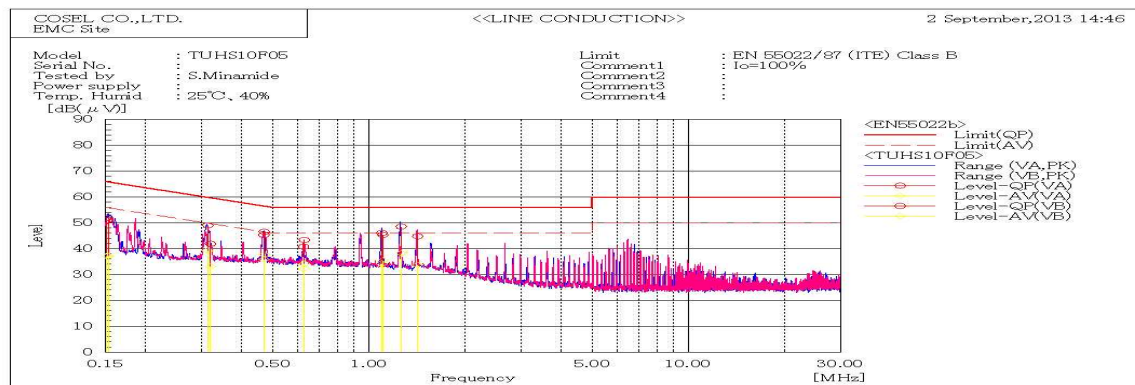
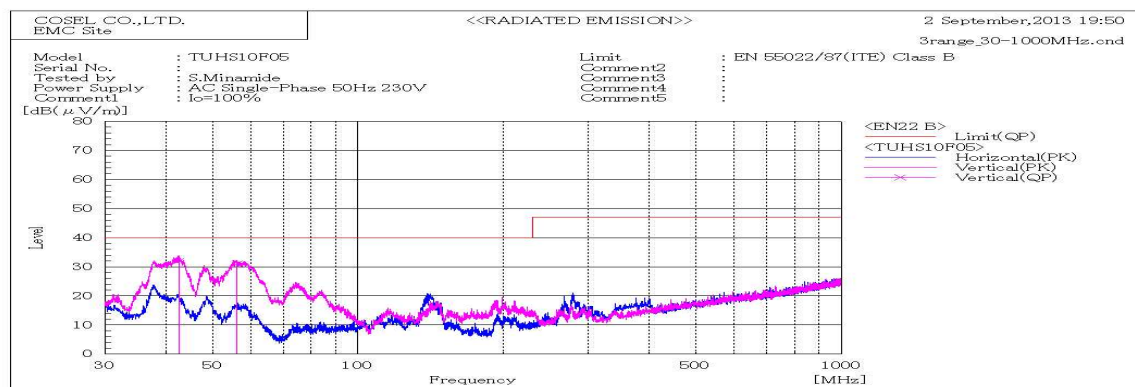


DATA SHEET		Date	16-Dec-13
Model	TUHS10F05	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide



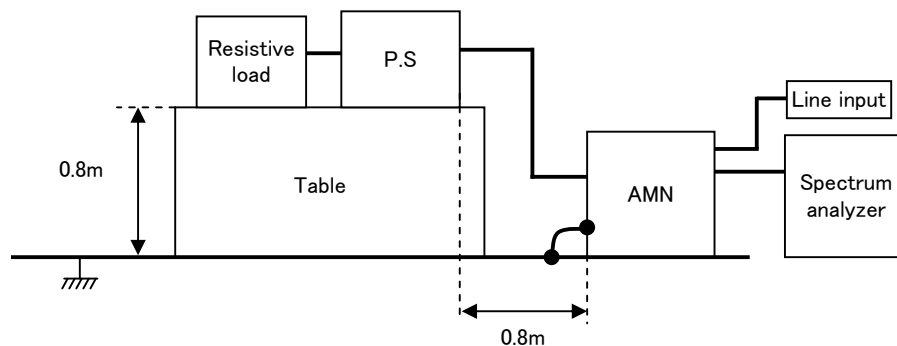
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.15099		VA	31.6	16.9	20.3	51.9	37.2	65.9	55.9	14.0	18.7	Pass	
0.15325		VB	30.9	17.0	20.2	51.1	37.2	65.8	55.8	14.7	18.6	Pass	
0.31374		VA	29.0	19.1	20.1	49.1	39.2	59.9	49.9	10.8	10.7	Pass	
0.32026		VB	21.8	13.1	20.1	41.9	33.2	59.7	49.7	17.8	16.5	Pass	
0.46977		VB	25.2	15.8	20.1	45.3	35.9	56.5	46.5	11.2	10.6	Pass	
0.47111		VA	26.5	17.6	20.1	46.6	37.7	56.5	46.5	9.9	8.8	Pass	
0.62583		VA	20.7	12.2	20.1	40.8	32.3	56.0	46.0	15.2	13.7	Pass	
0.6292		VB	23.3	14.0	20.1	43.4	34.1	56.0	46.0	12.6	11.9	Pass	
1.10728		VA	25.2	15.2	20.2	45.4	35.4	56.0	46.0	10.6	10.6	Pass	
1.09891		VB	25.9	14.0	20.2	46.1	34.2	56.0	46.0	9.9	11.8	Pass	
1.26334		VA	28.4	18.1	20.2	48.6	38.3	56.0	46.0	7.4	7.7	Pass	
1.42278		VB	24.6	13.5	20.2	44.8	33.7	56.0	46.0	11.2	12.3	Pass	



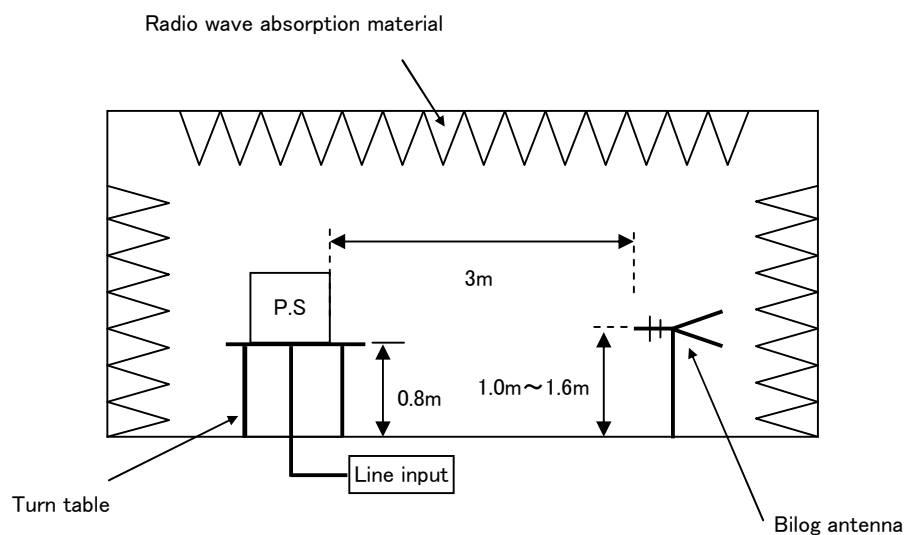
Frequency MHz	Polariz ation	Stabilit y	Reading dB(uV)	Factor dB(1/m)	Level dB(uV/m)	Limit dB(uV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
42.588	V	Stable	48.8	-16.7	32.1	40	7.9	Pass	102	323	
56.227	V	Stable	55	-23.9	31.1	40	8.9	Pass	103	85	

DATA SHEET		Date	16-Dec-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide

## 1. Line conduction



## 2. Radiated emission



## Conditions

Test: EMI

Model Name: TUHS10F□□

### ○ Photographs of Test Set-Up

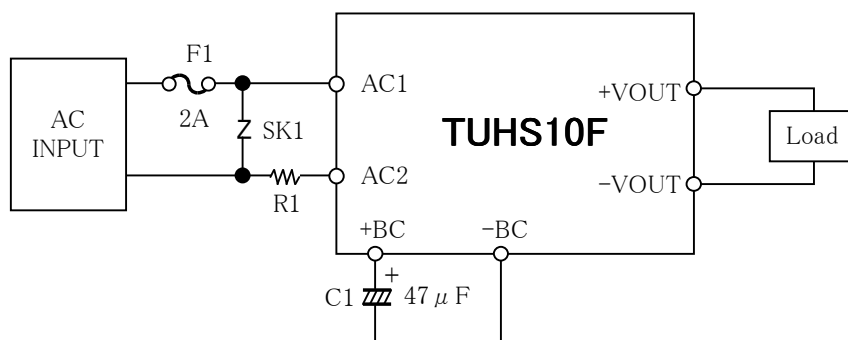
LINE CONDUCTION



RADIATED EMISSION



### ○ Test circuit



F1: SLT250V2A (Nippon Seisen)  
 R1: 2K100JA (TAMURA THERMAL DEVICE)  
 SK1: S10K385E2K1 (TDK EPCOS)

2A  
 10Ω

Fig.1 Testing circuitry